

Search Notes

Application/Control No.

10/782,846

Examiner

Shih-wen Hsieh

Applicant(s)/Patent under
Reexamination

LIN, TSUNG-TE

Art Unit

2861

SEARCHED

Class	Subclass	Date	Examiner
347	22-24,29 30,32,33 35	3/17/2005	<i>hnm</i> SWH

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR